

RF Exposure Report

Applicant Name: SAMSUNG Electronics Co., Ltd. 129, Samsung-ro, Yeongtong-gu, Suwon-Si, Gyeonggi-do, 16677 Rep. of Korea	Date of Issue: Nov. 12, 2021 Test Report No.: HCT-SR-2110-FC014-R1 Test Site: HCT CO., LTD.
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FCC ID:

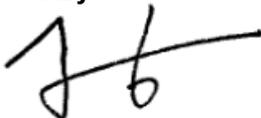
A3LSMN980F1

Equipment Type:	Mobile Phone
Application Type	Certification
FCC Rule Part(s):	FCC Part 1 SUBPART I FCC Part 2 SUBPART J KDB 680106 D01
Model Name:	SM-N980F/DS
Additional Model Name:	SM-N980F
Date of Test:	10/27/2021

This device has been shown to be capable of compliance for the above standards for uncontrolled environment/general population exposure limits specified in FCC KDB procedures and had been tested in accordance with the measurement procedures specified in FCC KDB procedures.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.

Tested By



Jung Hun, Park
Test Engineer
SAR Team
Certification Division

Reviewed By



Yun-jeang, Heo
Technical Manager
SAR Team
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DOCUMENT HISTORY

Rev.	DATE	DESCRIPTION
0	Oct. 29, 2021	First Approval Report
1	Nov. 12, 2021	Revised Sec.3.4

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1. Test Methodology

The DUT was assessed in accordance with FCC KDB 680106 D01 RF Exposure Wireless Charging Apps v03r01.

2. Test Location.

2.1 Test Laboratory.

Company Name:	HCT Co., LTD
Address:	74, Seoicheon-ro 578beon-gil, Majang-myeon, Icheon-si, Gyeonggi-do, 17383, Rep. of Korea
Telephone:	+82 31 645 6300
Fax.:	+82 31 645 6401

2.2 Test Facilities

Our laboratories are accredited and approved by the following approval agencies according to ISO/IEC 17025.

Korea:	National Radio Research Agency (Designation No. KR0032)
	KOLAS (Testing No. KT197)

3. DEVICE UNDER TEST DESCRIPTION

Applicant Name:	SAMSUNG Electronics Co., Ltd.
Model:	SM-N980F/DS
Additional Model Name:	SM-N980F
EUT Type:	Mobile Phone
Application Type:	Certification

3.1 Description of DUT

The DUT is a mobile phone with a WPT (Wireless Power Transfer) feature using an inductive charging coil to charge a phone or watch. The charging frequency is between 110 kHz to 148 kHz, and the maximum transfer power consumption is 9.0 W in charging status.

SM-N980F/DS, SM-N980F were tested and the worst case results are reported.
(Worst case :SM-N981B/DS)

3.2 WORST-CASE CONFIGURATION

Test configuration	Description
DUT to Phone test configuration 1	Charging from Phone to DUT
DUT to Phone test configuration 2	Charging from Phone to DUT(TA Charging from DUT)
DUT to Phone test configuration 3	Charging from Phone to DUT
DUT to Phone test configuration 4	Charging from Phone to DUT(TA Charging from DUT)
DUT to Phone test configuration 5	Charging from Watch to DUT
DUT to Phone test configuration 6	Charging from Watch to DUT(TA Charging from DUT)

Note :

1. Configuration 2,4 and 6 were tested with the worst case of configuration 1,3 and 5
2. All test configurations are with s-Pen inserted for charging.

3.3 KDB 680106 D01 v03 SECTION 5.b) EQUIPMENT APPROVAL CONSIDERATIONS

Requirement	Device
(1) Power transfer frequenc is less than 1 MHz.	Yes. Operation Frequency is between 110 kHz to 148 Khz.
(2) Output power from each primary coil is less than or equal to 15 watts.	Yes. Maximum power is 9.0 Watts.
(3) The transfer system includes onlt single primary and secondart coils. This includes charging systems that may have multiple primary coils and client that are able to detect and allow coupling only between individual pairs of coils	Yes.
(4) Client device is placed directly in contact with the transmitter.	Yes.
(5) Mobile expousure conditions only(portable exposure conditions are not convered by this exclusion).	Yes.
(6) The aggregate H-field strengths at 15 cm surrounding the device and 20 cm above the top surface from all simultaneous transmitting coils are demonstrated to be less than 50% of the MPE limit.	Yes. The aggregate field at 15 cm from the device are 5.67 % of the FCC H field limit.

3.4 DESCRIPTION OF TEST SETUP

SUPPORT EQUIPMENT & PERIPHERALS

SUPPORT EQUIPMENT & PERIPHERALS LIST				
Description	Manufacturer	Model	Serial Numver	FCC ID
Watch	SAMSUNG Electronics Co., Ltd.	SM-R835F	RFAM80Q6NJW	A3LSMR835
Phone	SAMSUNG Electronics Co., Ltd.	SM-G986B/DS	RF8M70ZA4FH	A3LSMG986B

TEST SETUP

The following three modes are tested in test configuration;

Mode
Operationg (SUPPORT Equipment, <10% Power Charging)
Operationg (SUPPORT Equipment, 50~55% Power Charging)
Operationg (SUPPORT Equipment, 90~95% Power Charging)

For Simultaneous Charging

All Position of client device were investigated and the worst position results are reported.

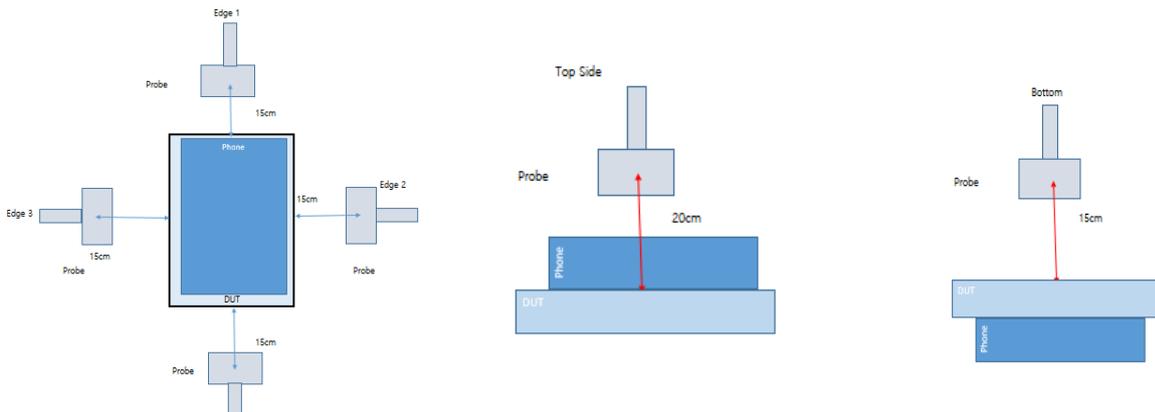
For S-Pen, both fully charged and non-fully charged condition were investigated. Test wer performed non-fully charged condition as worst case. Please refer to S-Pen Test report

MEASUREMENT TEST SETUP

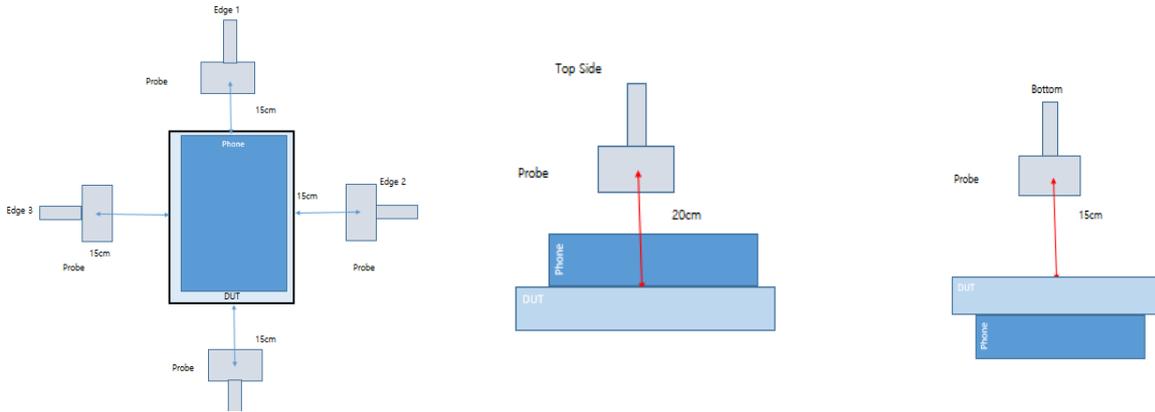
The measurement was taken using a probe place 15 cm from the edges of DUT or 20 cm above the DUT. Measurement were from the top and all sides of the DUT per KDB680106 D01 v03. Additionally, as the DUT to phone configuration could result with the DUT place either above or below the phone, measurements were performed 'below' th DUT by flipping the DUT/phone so that the DUT was uppermost.

The probe was moved along the edges or above the DUT to a position that showed the maximum field strength. This position was used for the reported resul.

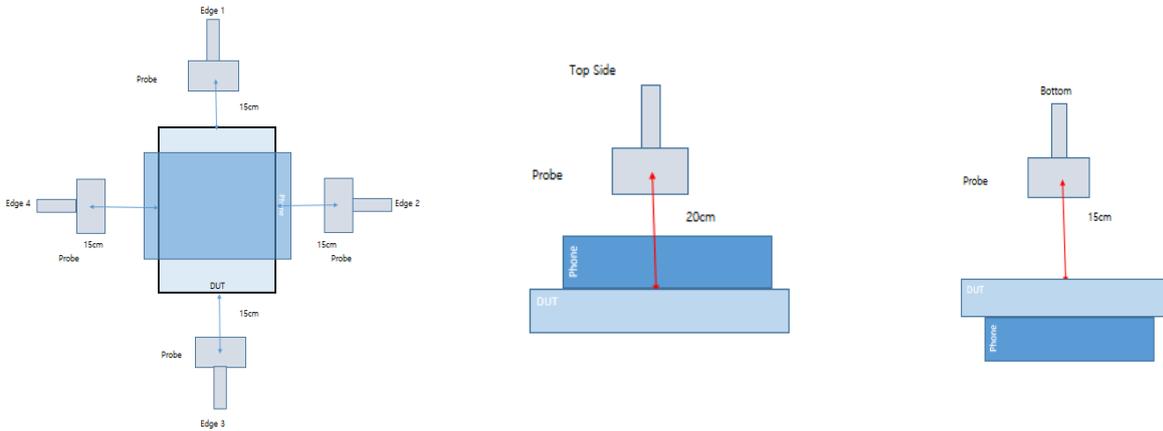
DUT to phone test Configuration 1 & 2



DUT to phone test Configuration 3 & 4



DUT to phone test Configuration 5 & 6



4. TEST AND MEASUREMENT EQUIPMENT

The following test and measurement equipment was used for the tests documented in this report :

Manufacturer	Model namr	Description	S/N	Calib. Date	Calib.Due
Narda	EHP-200AC	Electric and Magnetic Field Probe	170WX91009	11/22/2019	11/22/2021

The Narda EHP-200AC has physical dimensions of 92 x 92 x 109mm. So the center of the probe would be at 46 x 46 x 54mm. When the probe measures the H-field of the device,, the long axis of the probe (109mm) is perpendicular to the rear surface of the DUT. So when the probe is in direct contact with the rear of the device, the center of the probe would be 54mm away.

5. MAXIMUM PERMISSIBLE RE EXPOSURE

5.1 FCC RULES

1.13010 The criteria listed in Table 1 shall be used to evaluate the envirimental impact of human exposure to radio-frequency(RF) ragiation as specified in 1.1307(b), except in the case of portable devices which shall ge evaluated according th the provisions of 2.1093 of this chapter.

TABLE 1—LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm ²)	Averaging time (minutes)
(A) Limits for Occupational/Controlled Exposures				
0.3–3.0	614	1.63	*(100)	6
3.0–30	1842/f	4.89/f	*(900/f ²)	6
30–300	61.4	0.163	1.0	6
300–1500	f/300	6
1500–100,000	5	6
(B) Limits for General Population/Uncontrolled Exposure				
0.3–1.34	614	1.63	*(100)	30
1.34–30	824/f	2.19/f	*(180/f ²)	30

TABLE 1—LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)—Continued

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm ²)	Averaging time (minutes)
30–300	27.5	0.073	0.2	30
300–1500	f/1500	30
1500–100,000	1.0	30

f = frequency in MHz

* = Plane-wave equivalent power density

NOTE 1 TO TABLE 1: Occupational/controlled limits apply in situations in which persons are exposed as a consequence of their employment provided those persons are fully aware of the potential for exposure and can exercise control over their exposure. Limits for occupational/controlled exposure also apply in situations when an individual is transient through a location where occupational/controlled limits apply provided he or she is made aware of the potential for exposure.

NOTE 2 TO TABLE 1: General population/uncontrolled exposures apply in situations in which the general public may be exposed, or in which persons that are exposed as a consequence of their employment may not be fully aware of the potential for exposure or can not exercise control over their exposure.

6. TEST RESULTS

H-Field Measurements

Note : peak measurements were performed. RMS values were calculated from the peak measurement.

Please refer to the formula for calculating the RMS value: [Field Strength * $\sqrt{\text{Duty Cycle}}$]

TEST results of DUT to phone test Configuraion 1 &2

FCC RF Exposurs Result					
Test Configuration	Test mode	The Distance from the edge of the device to the center of the probe (cm)	Test Position	H-Field Limit (A/m)	H-Field meas data (A/m)
Configuration 1	Operation Real Product (Power <10% charging)	20 cm	Top	1.63	0.0376
		15 cm	Bottom		0.0414
			Edge 1		0.0380
			Edge 2		0.0696
			Edge 3		0.0412
			Edge 4		0.0853
	Operation Real Product (Power 50~55% charging)	20 cm	Top	1.63	0.0350
		15 cm	Bottom		0.0368
			Edge 1		0.0376
			Edge 2		0.0738
			Edge 3		0.0389
			Edge 4		0.0848
	Operation Real Product (Power 90~95% charging)	20 cm	Top	1.63	0.0390
		15 cm	Bottom		0.0373
			Edge 1		0.0360
			Edge 2		0.0681
			Edge 3		0.0388
			Edge 4		0.0849
Configuration 2	Operation Real Product (Power <10% charging)	15 cm	Edge 4	1.63	0.0836

TEST results of DUT to phone test Configuraion 3 &4

FCC RF Exposurs Result					
Test Configuration	Test mode	The Distance from the edge of the device to the center of the probe (cm)	Test Position	H-Field Limit (A/m)	H-Field meas data (A/m)
Configuration 3	Operation Real Product (Power <10% charging)	20 cm	Top	1.63	0.0556
		15 cm	Bottom		0.0367
			Edge 1		0.0404
			Edge 2		0.0766
			Edge 3		0.0388
			Edge 4		0.0925
	Operation Real Product (Power 50~55% charging)	20 cm	Top	1.63	0.0536
		15 cm	Bottom		0.0328
			Edge 1		0.0417
			Edge 2		0.0806
			Edge 3		0.0365
			Edge 4		0.0903
	Operation Real Product (Power 90~95% charging)	20 cm	Top	1.63	0.0555
		15 cm	Bottom		0.0389
			Edge 1		0.0426
Edge 2			0.0788		
Edge 3			0.0371		
Edge 4			0.0907		
Configuration 4	Operation Real Product (Power <10% charging)	15 cm	Edge 4	1.63	0.0836

TEST results of DUT to phone test Configuraion 5 &6

FCC RF Exposurs Result					
Test Configuration	Test mode	The Distance from the edge of the device to the center of the probe (cm)	Test Position	H-Field Limit (A/m)	H-Field meas data (A/m)
Configuration 5	Operation Real Product (Power <10% charging)	20 cm	Top	1.63	0.0675
		15 cm	Edge 1		0.0413
			Edge 2		0.0442
			Edge 3		0.0422
			Edge 4		0.0382
	Operation Real Product (Power 50~55% charging)	20 cm	Top	1.63	0.0673
		15 cm	Edge 1		0.0353
			Edge 2		0.0382
			Edge 3		0.0402
	Operation Real Product (Power 90~95% charging)	20 cm	Top	1.63	0.0655
		15 cm	Edge 1		0.0328
			Edge 2		0.0379
Edge 3			0.0417		
Configuration 6	Operation Real Product (Power <10% charging)	15 cm	Top	1.63	0.0664
			Edge 1		0.0328
			Edge 2		0.0379
			Edge 3		0.0417

6.2 FCC SUMMARY OF RESULTS

H-Field Limit		
FCC RF Exposure	Maximum meas data (A/m)	Percentage(%)
1.63	0.0925	5.67

H-Field test result was less than 50% of MPE limit